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Application Number 09/888,093

**INFORMATION DISCLOSURE CITATION
IN AN APPLICATION**

Applicant

John S. JUDGE et al.

Filing Date June 21, 2001

Group Art Unit 2652

Mailing Date

8/13/03

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
AC	1.	4/8/1986	4,581,729	Beaujean			
AC	2.	9/1/1998	5,802,033	Van Rosmalen			

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO
AC	3.	7/14/1993	0 551 072 A1	EPO			

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
AC	4.	JP 05 250659 A, 9/28/1993, abstract, Derwent Publ. Ltd. London, GB, XP002244021, 1 pg.

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EXAMINER: ANGEL CASTRO

DATE CONSIDERED: 4/4/05

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified) OCT 10 2001 PATENT & TRADEMARK OFFICE (37 CFR 1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 06837-112001	Application No. 09/888,093
	Information Disclosure Statement by Applicant (Use several sheets if necessary)		
	Applicant John S. Judge et al.		Filing Date June 22, 2001

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
AC	AA	5,063,097	11/05/91	Hirota et al.			
AC	AB	5,098,761	03/24/92	Watanabe et al.			
AC	AC	5,124,232	06/23/92	Nakanishi et al.			
AC	AD	5,187,052	02/16/93	Maeda et al.			
AC	AE	5,362,538	11/08/94	Ohbayashi et al.			
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AC	AK	6,040,066	03/21/00	Zhou et al.			
AC	AL	6,071,588	06/06/00	Nobumasa et al.			
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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
AC	AN	WO 99/24975	05/20/99	WIPO				
AC	AO	WO 99/30317	06/17/99	WIPO				
	AP							
	AQ							
	AR							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
AC	AS	Khulbe, Pramod et al., "Crystallization and amorphization studies of a Ge ₂ Sb _{2.3} Te ₃ thin-film sample under pulsed laser irradiation", <i>Applied Optics</i> , Vol. 39, No. 14, (2000)
AC	AT	Ohta, Takeo et al., "Overwritable Phase-Change Optical Disk Recording", <i>IEEE Transactions On Magnetics</i> , Vol. 34, No. 2, (1998)

Examiner Signature ANGEL CASTRO	Date Considered 4/4/05
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